

ADVANCED INFORMATION

DESCRIPTION:

The DPD16ML36PL5 and the DPD16ML36PW5 are the Low Profile 16 Meg x 36 Dynamic RAM module in the family of *SuperSIMM*[™] modules that utilize the new and innovative space saving TSOP stacking technology. The module is constructed of eight dynamic RAM stacks surface mounted on an industry standard 72-pin SIMM and ZIP substrates and, with eight stacks consisting of four 16 Meg x 1 Dynamic RAM's.

The DPD16ML36PL5/DPD16ML36PW5 provides for a compatible upgrade path from lower density JEDEC compatible modules. The module features high speed access times, common data inputs and outputs, Fully Buffered Address and Write Enable, $\overline{\text{RAS}}$, $\overline{\text{CAS}}$ and power decoupling capacitors.

FEATURES:

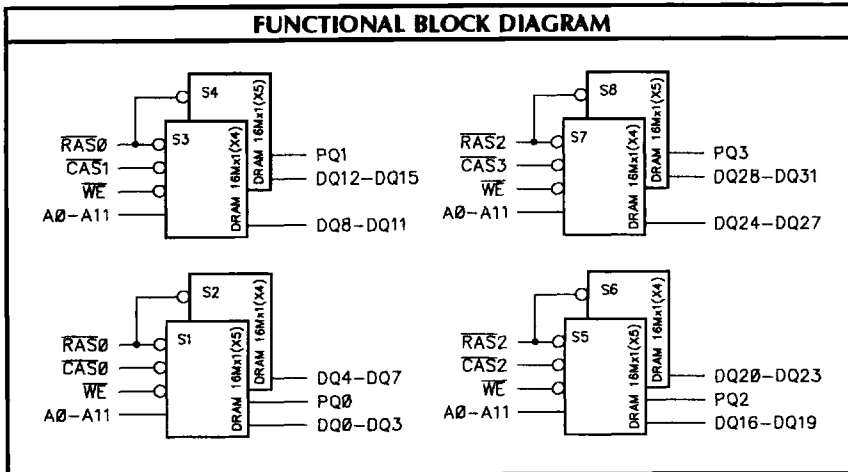
- Access Times:
70, 80, 100ns (max.)
- Single 5V ($\pm 5\%$) Supply
- Common Data Inputs and Outputs
- Fast Page Mode Capability
- 4096 Cycles / 64 ms
- 3 variations of Refresh:
 - $\overline{\text{RAS}}$ only Refresh
 - $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh
 - Hidden Refresh
- Packages Available:
Industry Standard 72-Pin SIMM
Industry Standard 72-Pin ZIP

PIN NAMES	
A0 - A11	Row Address: A0 - A11 Column Address: A0 - A11 Refresh Address: A0 - A11
DQ0 - DQ31	Data In / Data Out
PQ0 - PQ3	Parity Data In / Data Out
$\overline{\text{CAS}}0 - \overline{\text{CAS}}3$	Column Address Strokes
$\overline{\text{RAS}}0, \overline{\text{RAS}}2$	Row Address Enables
WE	Read / Write Enable
VDD	Power Supply (+5V)
Vss	Ground
PD1 - PD4	Presence Detect Pin
N.C.	No Connect

PIN-OUT DIAGRAM

TOP VIEW		
INDEX	1	VSS
DQ0	2	
DQ1	4	3 DQ16
DQ2	6	5 DQ17
DQ3	8	7 DQ18
VDD	10	9 DQ19
A0	12	11 N.C.
A2	14	13 A1
A4	16	15 A3
A6	18	17 A5
DQ4	20	19 A10
DQ5	22	21 DQ20
DQ6	24	23 DQ21
DQ7	26	25 DQ22
A7	28	27 DQ23
VDD	30	29 A11
A9	32	31 A8
$\overline{\text{RAS}}2$	34	33 N.C.
PQ0	36	35 PQ2
		37 PQ1
PQ3	38	39 VSS
$\overline{\text{CAS}}0$	40	41 $\overline{\text{CAS}}2$
$\overline{\text{CAS}}3$	42	43 $\overline{\text{CAS}}1$
$\overline{\text{RAS}}0$	44	45 N.C.
N.C.	46	47 $\overline{\text{WE}}$
N.C.	48	49 DQ8
DQ24	50	51 DQ9
DQ25	52	53 DQ10
DQ26	54	55 DQ11
DQ27	56	57 DQ12
DQ28	58	59 VDD
DQ29	60	61 DQ13
DQ30	62	63 DQ14
DQ31	64	65 DQ15
PD2	66	67 PD1
PD4	68	69 PD3
N.C.	70	71 N.C.
VSS	72	

FUNCTIONAL BLOCK DIAGRAM



ADVANCED INFORMATION

ABSOLUTE MAXIMUM RATINGS			
Symbol	Parameter	Value	Units
T _{STC}	Storage Temperature	-55 to +150	°C
V _{IO}	Voltage on Any Pin	-1.0 to +7.0	V
V _{DD}	V _{DD} Supply Voltage	-1.0 to +7.0	V
I _{OUT}	Output Current	50	mA

RECOMMENDED OPERATING CONDITIONS					
Symbol	Parameter	Min.	Typ.	Max.	Units
V _{DD}	Supply Voltage	4.5	5.0	5.5	V
V _{IL}	Input Low Voltage	-1.0		0.8	V
V _{IH}	Input High Voltage	2.4		V _{DD} +1.0	V
T _A	Operating Temperature	0	+25	+70	°C

NOTE: All voltages referenced to V_{SS}.

CAPACITANCE: t _A = 25°C, f = 1MHz				
Symbol	Parameter	Max	Unit	Condition
C _{ADR}	Address Input	30	pF	V _{IN} = 0V
C _{CAS}	CAS Input	80		
C _{RAS}	RAS Input	145		
C _{WE}	Write Enable	30		
C _{IO}	Data Input/Output	30		

AC TEST CONDITIONS	
Input Pulse Levels	0V to 3.0V
Input Pulse Rise and Fall Times	5ns *
Input Timing Reference Levels	1.5V
Output Timing Reference Levels	1.5V

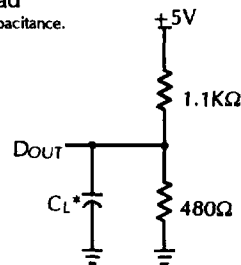
* Transition measured between 0.8V and 2.2V.

PRESENCE DETECT PINS			
PIN	70ns	80ns	100ns
PD1	V _{SS}	V _{SS}	V _{SS}
PD2	OPEN	OPEN	OPEN
PD3	V _{SS}	OPEN	V _{SS}
PD4	OPEN	V _{SS}	V _{SS}

OUTPUT LOAD		
Load	CL	Parameters Measured
1	100pF	except t _{CLZ}
2	5pF	t _{CLZ}

Figure 1. Output Load

** Including Scope and Jig Capacitance.



DC OPERATING CHARACTERISTICS									
Symbol	Characteristic	Conditions	70ns		80ns		100ns		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
I _{IN}	Input Leakage Current	CAS	-90	90	-90	90	-90	90	μA
		RAS	-180	180	-180	180	-180	180	μA
		A0 - A11, WE	-20	20	-20	20	-20	20	
I _{OUT}	Output Leakage Current		-10	10	-10	10	-10	10	μA
I _{CC1}	Operating Current	RAS and CAS cycling @ t _{rc} = min.		3240		2880		2560	mA
I _{CC2}	Standby Current	RAS = CAS = WE = V _{IH}		72		72		72	mA
I _{CC3}	RAS - Only Refresh Current	CAS = V _{IH} , RAS Cycling @ t _{rc} = min.		3240		2880		2560	mA
I _{CC4}	FAST-PAGE-MODE Current	RAS = V _{IL} , CAS, Address Cycling @ t _{pc} = min.		2880		2520		2360	mA
I _{CC5}	Standby Current	RAS = CAS = WE = V _{DD} -0.2V		36		36		36	mA
I _{CC6}	CAS - Before - RAS Refresh Current	RAS and CAS Cycling @ t _{rc} = min.		3240		2880		2560	mA
V _{OL}	Output Low Voltage	I _{OL} = 4.2mA		0.4		0.4		0.4	V
V _{OH}	Output High Voltage	I _{OH} = -5mA	2.4		2.4		2.4		V

ADVANCED INFORMATION

A.C. OPERATING AND CHARACTERISTICS ($V_{DD} = 5.0V \pm 10\%$, $T_A = 0^\circ C$ to $70^\circ C$)									
No.	Symbol	Parameter	60ns		70ns		80ns		Unit
			Min.	Max.	Min.	Max.	Min.	Max.	
1	t _{RC}	Random Read or Write Cycle Time	110		130		150		ns
2	t _{RAC}	Access Time from \overline{RAS} ^{3, 4, 9}		60		70		80	ns
3	t _{CAC}	Access Time from \overline{CAS} ^{3, 4, 9}		15		20		20	ns
4	t _{AA}	Access Time from Column Address ^{3, 9}		35		40		45	ns
5	t _{CLZ}	\overline{CAS} to Output in LOW-Z ³	0		0		0		ns
6	t _{OFF}	Output Buffer Turn-Off Delay Time ⁶	0	15	0	20	0	20	ns
7	t _T	Transition Time (Rise and Fall) ²	3	50	3	50	3	50	ns
8	t _{RP}	\overline{RAS} Precharge Time	40		50		60		ns
9	t _{RAS}	\overline{RAS} Pulse Width	60	10,000	70	10,000	80	10,000	ns
10	t _{RSH}	\overline{RAS} Hold Time	15		20		20		ns
11	t _{CSH}	\overline{CAS} Hold Time	60		70		80		ns
12	t _{CAS}	\overline{CAS} Pulse Width	15	10,000	20	10,000	20	10,000	ns
13	t _{RCd}	\overline{RAS} to \overline{CAS} Delay Time ⁴	20	45	20	50	20	60	ns
14	t _{RAd}	\overline{RAS} to Column Address Delay Time ⁹	15	30	15	35	15	40	ns
15	t _{CRP}	\overline{CAS} to \overline{RAS} Precharge Time	5		5		5		ns
16	t _{ASR}	Row Address Setup Time	0		0		0		ns
17	t _{RAH}	Row Address Hold Time	10		10		10		ns
18	t _{ASC}	Column Address Setup Time	0		0		0		ns
19	t _{CAH}	Column Address Hold Time	10		15		15		ns
20	t _{AR}	Column Address Hold Time Referenced to \overline{RAS} ¹²	50		55		60		ns
21	t _{RAI}	Column Address to \overline{RAS} Lead Time	30		35		40		ns
22	t _{RCS}	Read Command Setup Time	0		0		0		ns
23	t _{RCH}	Read Command Hold Time Referenced to \overline{CAS} ⁷	0		0		0		ns
24	t _{RRH}	Read Command Hold Time Referenced to \overline{RAS}	0		0		0		ns
25	t _{WCH}	Write Command Hold Time	10		15		15		ns
26	t _{WCR}	Write Command Hold Time Referenced to \overline{RAS} ¹²	55		60		60		ns
27	t _{WP}	Write Command Pulse Width	10		15		15		ns
28	t _{RWL}	Write Command to \overline{RAS} Lead Time	55		20		20		ns
29	t _{CWL}	Write Command to \overline{CAS} Lead Time	15		20		20		ns
30	t _{DS}	Data-In Setup Time ⁸	0		0		0		ns
31	t _{DH}	Data-In Hold Time ⁸	10		15		15		ns
32	t _{DHR}	Data-In Hold Time Referenced to \overline{RAS} ¹²	55		60		60		ns
33	t _{REF}	Refresh Period		64		64		64	ms
34	t _{WCS}	Write Command Setup Time	0		0		0		ns
35	t _{CSR}	\overline{CAS} Setup Time (C-B-R Refresh)	10		10		10		ns

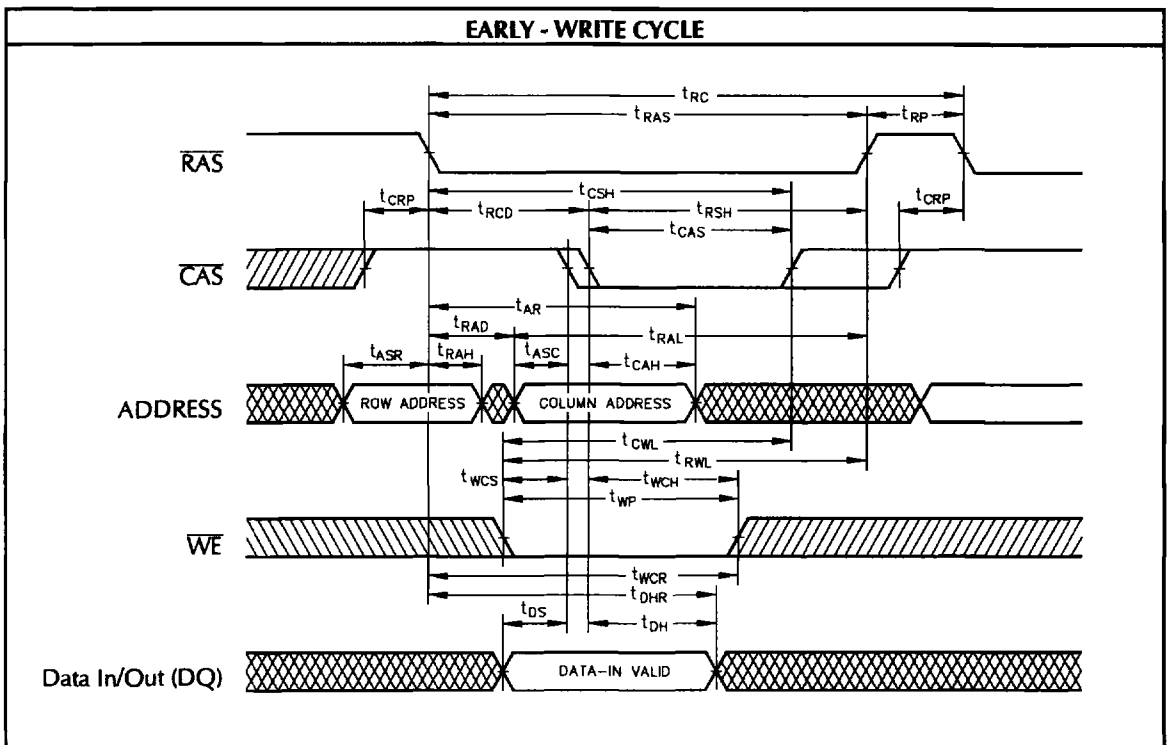
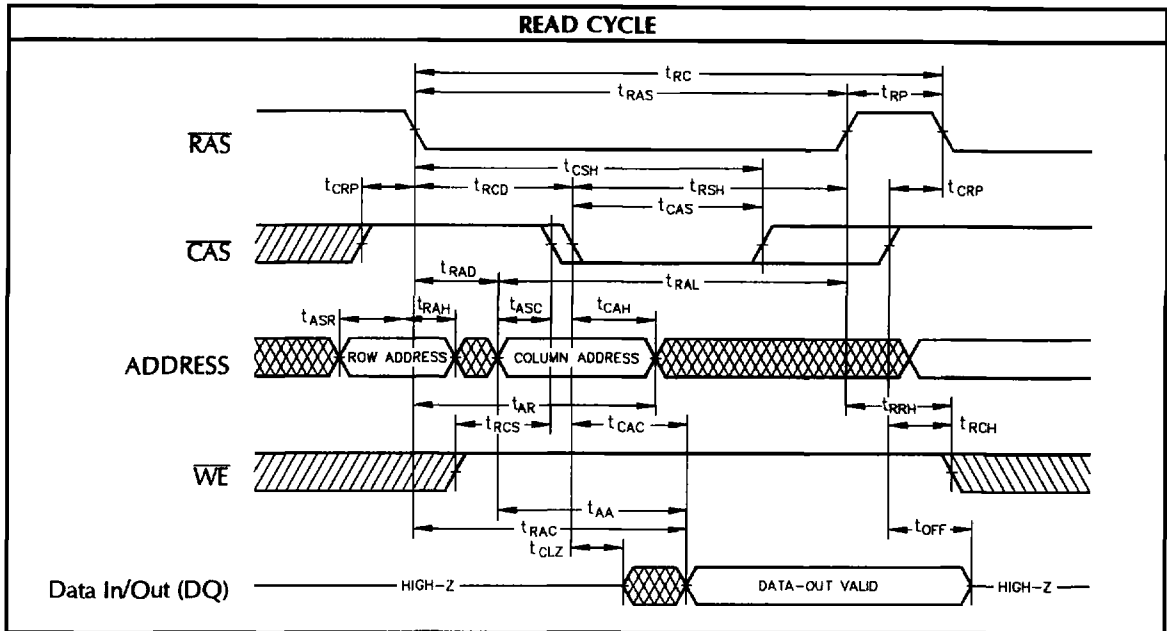
ADVANCED INFORMATION

A.C. OPERATING AND CHARACTERISTICS ($V_{DD} = 5.0V \pm 10\%$, $T_A = 0^\circ C$ to $70^\circ C$) (Continued)									
No.	Symbol	Parameter	60ns		70ns		80ns		Unit
			Min.	Max.	Min.	Max.	Min.	Max.	
36	t _{CHR}	CAS Hold Time (C-B-R Refresh)	15		15		15		ns
37	t _{RPC}	RAS to CAS Precharge Time	5		5		5		ns
38	t _{CPA}	Access Time from CAS Precharge ³		35		40		45	ns
39	t _{PC}	FAST - PAGE - MODE Cycle Time	40		45		50		ns
40	t _{CP}	CAS Precharge Time (Fast Page Cycle)	10		10		10		ns
41	t _{RASP}	RAS Pulse Width (Fast Page Cycle)	60	200,000	70	200,000	80	200,000	ns
42	t _{RHCP}	RAS Hold Time from CAS Precharge	35		40		45		
43	t _{WRP}	WE to RAS Precharge Time (C-B-R Refresh)	10		10		10		ns
44	t _{WRH}	WE to RAS Hold Time (C-B-R Refresh)	10		10		10		ns
45	t _{RASS}	RAS Pulse Width (C-B-R Refresh) ¹¹	100		100		100		µs
46	t _{RPS}	RAS Precharge Time (C-B-R Refresh) ¹¹	110		130		150		ns
47	t _{CHS}	CAS Hold Time (C-B-R Refresh) ¹¹	-50		-50		-50		ns

NOTES:

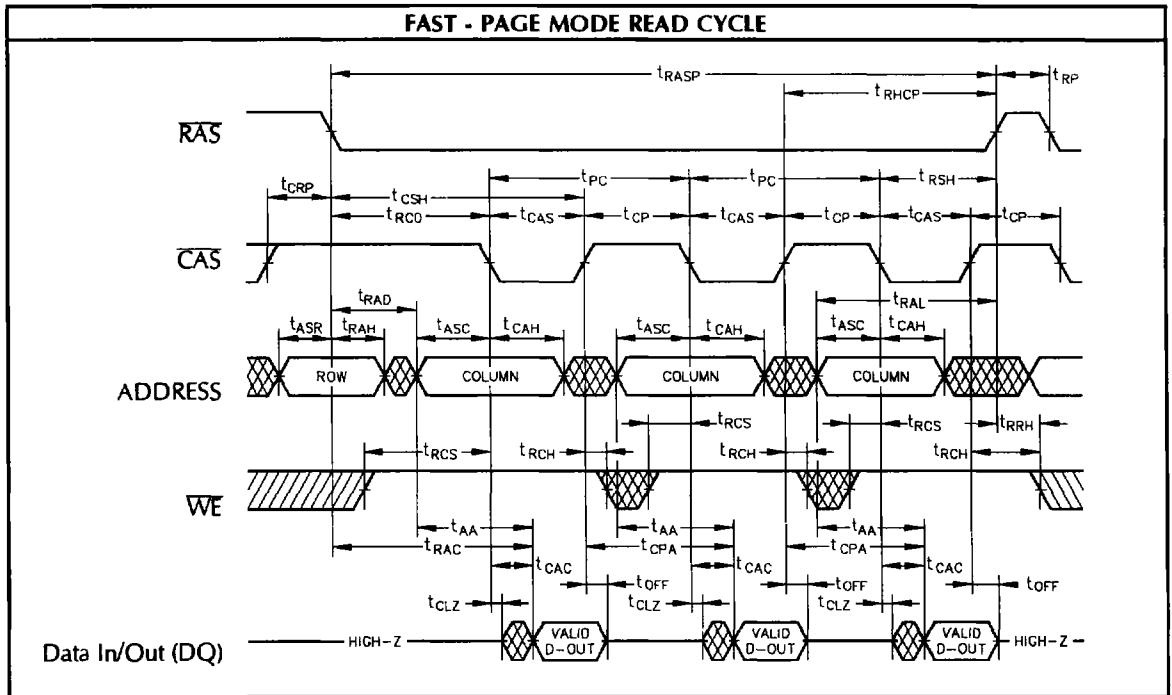
1. An initial pause of 200µs is required after power-up followed by eight RAS refresh cycles (RAS-ONLY or CBR) before proper operation is assured.
2. V_{IH} (min.) and V_{IL} (max.) are reference levels for measuring timing of input signals. Transition times are measured between V_{IH} (min.) and V_{IL} (max.) and are assumed to be 5ns for all inputs.
3. Measured with the load equivalent to (2) two TTL loads and 100pF.
4. Operation within the t_{RCD} (max.) limit ensures that t_{RAC} (max.) can be met. t_{RCD} (max.) is specified as a reference point only. If t_{RCD} is greater than the specified t_{RCD} (max.) limit, then access time is controlled exclusively by t_{CAC}.
5. Assumes that t_{RCD} ≥ t_{RCD} (max.).
6. This parameter defines the time at which the output achieves the open circuit conditions and is not referenced to V_{OL} or V_{OH}.
7. Either t_{RCH} or t_{RRH} must be satisfied for a READ cycle.
8. These parameters are referenced to the CAS leading edge in EARLY-WRITE cycles and to the WE leading edge in READ-MODIFY-WRITE cycles
9. Operation within the t_{RAD} (max.) limit insures that t_{RAC} (max.) can be met. If t_{RAD} is specified as a reference point only. If t_{RAD} is greater than the specified t_{RAD} (max.) limit, access time is controlled exclusively by t_{AA}.
10. t_{OFF} (max.) defines the time at which the output achieves the open circuit condition and is not a reference to output voltage level.
11. 4096 cycles of burst refresh must be executed within 16ms before and after self refresh, in order to meet refresh specification.
12. t_{AR}, t_{WCR}, and t_{DHR} are references to t_{RAD} (max.).

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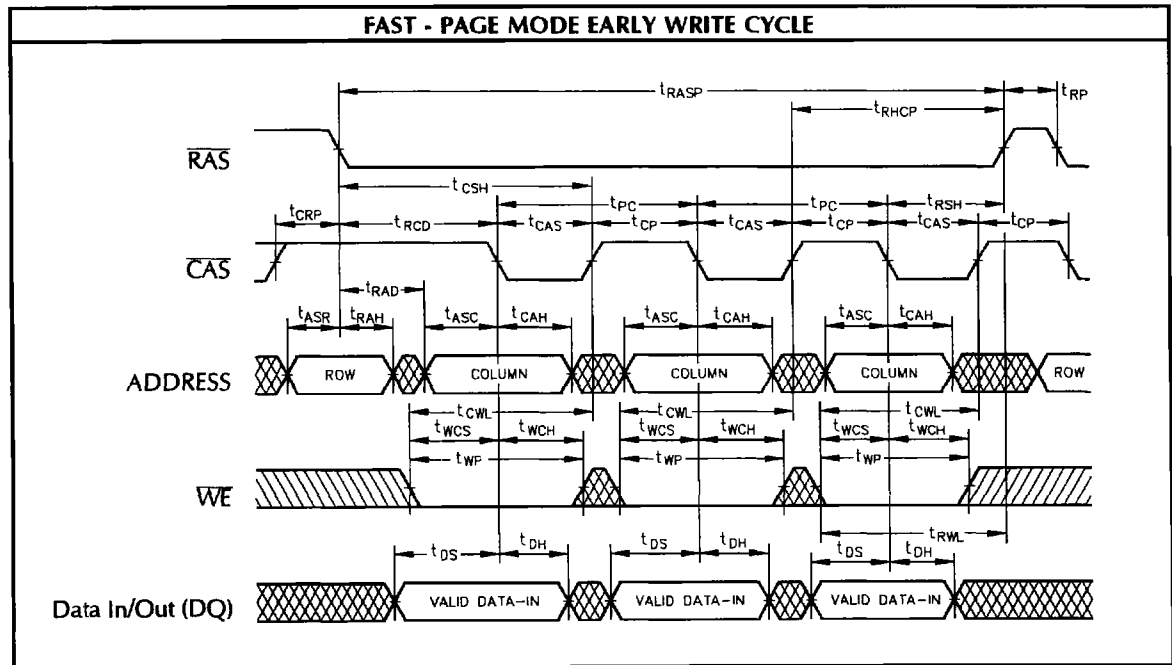


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FAST - PAGE MODE READ CYCLE

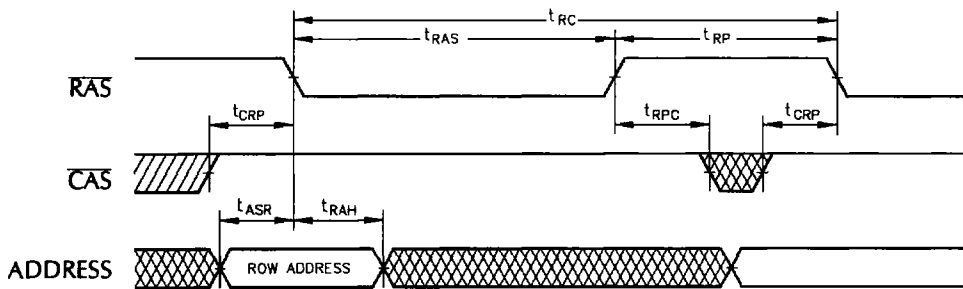


FAST - PAGE MODE EARLY WRITE CYCLE

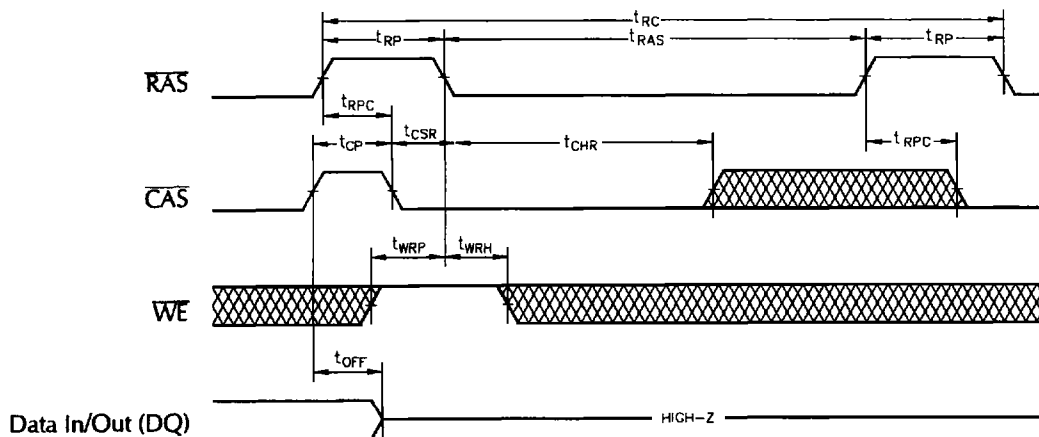


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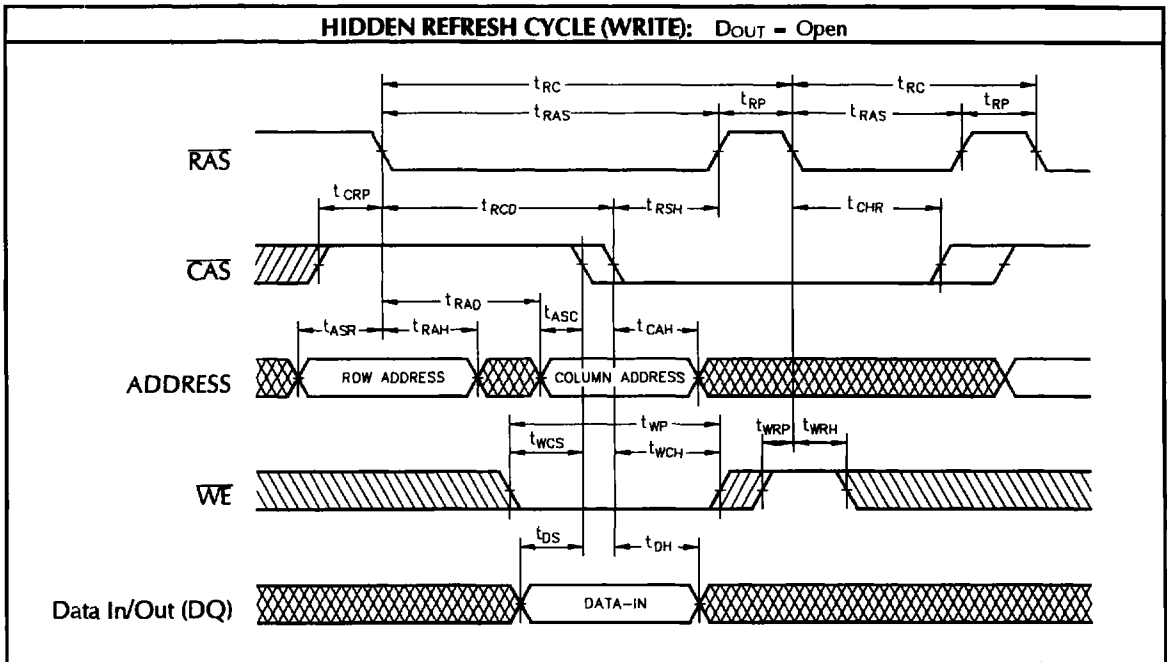
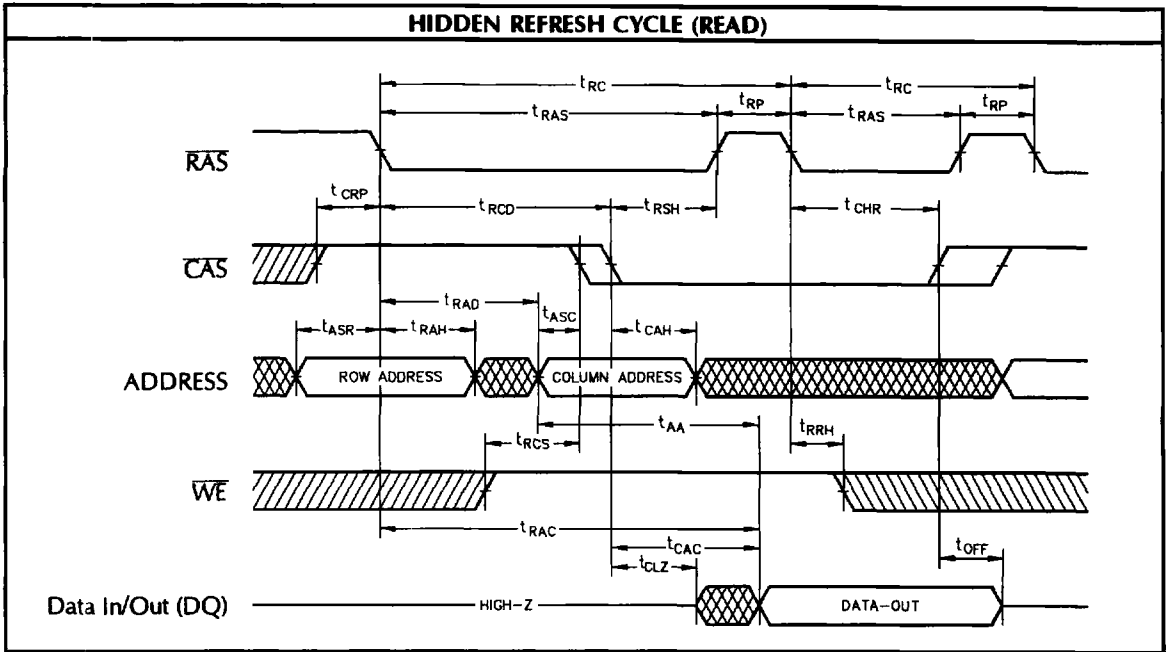
$\overline{\text{RAS}}$ - ONLY REFRESH CYCLE: $\overline{\text{WE}}$, DIN - Don't Care: DOUT - Open



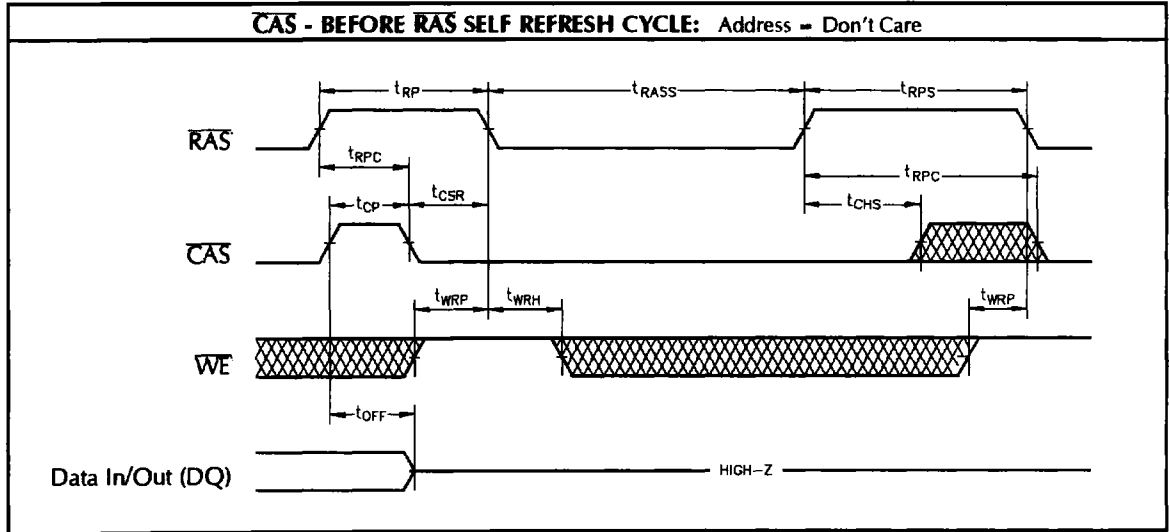
$\overline{\text{CAS}}$ - BEFORE $\overline{\text{RAS}}$ REFRESH CYCLE: Address - Don't Care



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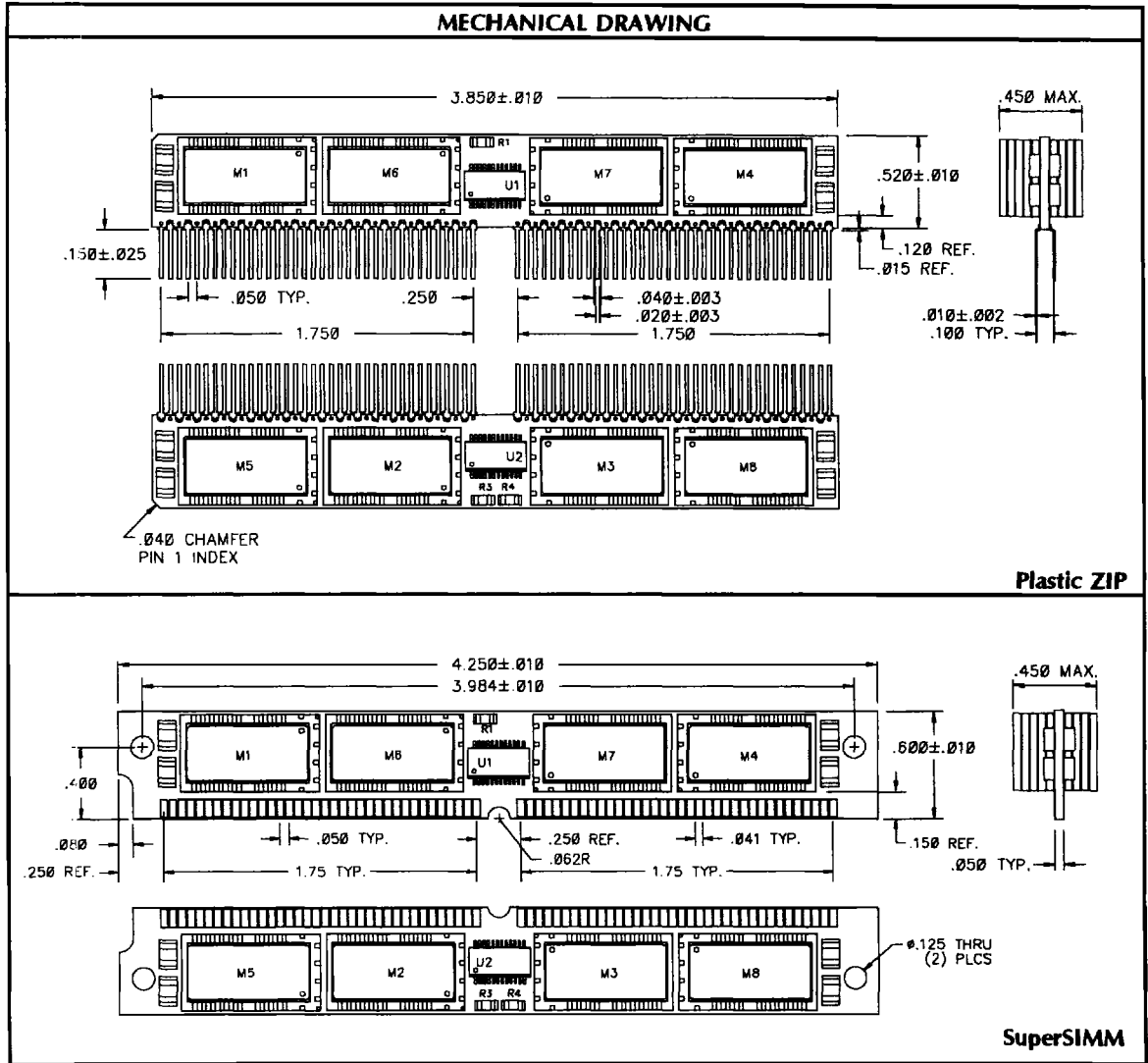


ORDERING INFORMATION

DP D 16M L 36 P W5 - XX C
 PREFIX TYPE MEMORY DEPTH DESIG MEMORY WIDTH DESIG PACKAGE SPEED GRADE

- C COMMERCIAL 0°C to +70°C
- 70 70ns
- 80 80ns
- 10 100ns
- L 72-PIN Plastic ZIP / TSOP STACKING
- W 72-PIN SuperSIMM / TSOP STACKING
- 16 MEGABIT BASED
- LOW PROFILE MODULE WITH SUPPORT LOGIC
- CMOS DRAM

ADVANCED INFORMATION



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